

iMiD 2025

The 25th International Meeting on Information Display
August 19-22, 2025 / BEXCO, BUSAN, KOREA

Session Title:	22. AI for Display Inspection
Session Date:	August 21 (Thu.), 2025
Session Time:	09:00–10:25
Session Room:	Room F (313)
Session Chair(s):	Prof. Hogun Park (Sungkyunkwan Univ., Korea) Dr. Rahul Shenoy (Samsung Display Co., Ltd., America Lab, USA)

[F22-1] [Invited]	09:00–09:30
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Zero-Shot Defect Transfer in Display Backplanes Using Diffusion Models

Rahul Shenoy, Zhihong Pan, Kaushik Balakrishnan (Samsung Display Co., Ltd., America Lab, USA), Yongmoon Jeon, Heejune Yang, and Jaewon Kim (Samsung Display Co., Ltd., Korea)

[F22-2] [Invited]	09:30–09:55
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Leveraging Multimodal Large Language Models for Advanced Anomaly Detection and Defect Analysis

Hyunju Kang, Woohyun Lee, and Hogun Park (Sungkyunkwan Univ., Korea)

[F22-3]	09:55–10:10
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Analysis of Ink Flow Using Artificial Intelligence in 200ppi Sub-Pixel Display based on Inkjet Printing Process

Sung Jun Park, Jin Hong Park, Seong Woo Jeong, Seok Hwan Jang (Gyeongsang Nat'l Univ., Korea), Kunsik An (Sejong Univ., Korea), and Jun Young Kim (Gyeongsang Nat'l Univ., Korea)

[F22-4]	10:10–10:25
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3D Profile Prediction for Inkjet-Printed OLEDs Thin Film from Microscopic Image Using Deep Learning

Dong Yeol Shin (Korea Univ. & KITECH, Korea), Youngwook Noh, Kwan Hyun Cho (KITECH, Korea), Byeong-Kwon Ju (Korea Univ., Korea), and Kyung-Tae Kang (KITECH, Korea)